

**Notice of References Cited**

Application/Control No.

09/927,011

Applicant(s)/Patent Under  
Reexamination  
BARTENSTEIN ET AL.

Examiner

R. Stephen Dildine

Art Unit

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Page 1 of 1

**U.S. PATENT DOCUMENTS**

| * |   | Document Number<br>Country Code-Number-Kind Code | Date<br>MM-YYYY | Name                 | Classification |
|---|---|--|-----------------|----------------------|----------------|
|   | A | US-2002/0184580 A1                               | 12-2002         | Archibald et al.     | 714/719        |
|   | B | US-5,912,901 A                                   | 06-1999         | Adams et al.         | 714/733        |
|   | C | US-5,991,215 A                                   | 11-1999         | Brunelle, Steven J.  | 365/201        |
|   | D | US-6,636,998 B1                                  | 10-2003         | Lee et al.           | 714/735        |
|   | E | US-6,195,771 B1                                  | 02-2001         | Tanabe et al.        | 714/718        |
|   | F | US-5,954,830 A                                   | 09-1999         | Ternullo, Jr., Luigi | 714/718        |
|   | G | US-  |                 |                      |                |
|   | H | US-  |                 |                      |                |
|   | I | US-  |                 |                      |                |
|   | J | US-  |                 |                      |                |
|   | K | US-  |                 |                      |                |
|   | L | US-  |                 |                      |                |
|   | M | US-  |                 |                      |                |

**FOREIGN PATENT DOCUMENTS**

| * |   | Document Number<br>Country Code-Number-Kind Code | Date<br>MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
|   | N |  |                 |         |      |                |
|   | O |  |                 |         |      |                |
|   | P |  |                 |         |      |                |
|   | Q |  |                 |         |      |                |
|   | R |  |                 |         |      |                |
|   | S |  |                 |         |      |                |
|   | T |  |                 |         |      |                |

**NON-PATENT DOCUMENTS**

| * |   | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)  |
|---|---|--|
|   | U | TDB-ACC-NO: NNRD439133; A method for scan based memory test to supplement built-in self-test; IBM technical Disclosure Bulletin, Issue Number 439; November 2000, UK; page 2015  |
|   | V | Matsumura, T.; An efficient test method for embedded multi-port RAM with BIST circuitry; □□Memory Technology, Design and Testing, 1995., Records of the 1995 IEEE International Workshop on , 7-8 Aug. 1995; Pages:62 - 67 |
|   | W |  |
|   | X |  |

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.